

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael P. Chrisp Docket No. : IL-11127
Serial No. : Art Unit :
Filed : Examiner :
For : COMPACT REFLECTIVE IMAGING SPECTROMETER
UTILIZING IMMERSED GRATINGS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

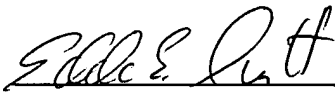
Dear Sir:

Forwarded herewith is an Information Disclosure Statement, Form-1449, in the above-identified application. Copies of the cited references are enclosed: 14 U.S. Patent Documents and 1 Foreign Patent Document.

The above-mentioned disclosures, which are not admitted as prior art, are identified on the enclosed Form 1449.

Respectfully submitted,

Dated: September 8, 2003


Eddie E. Scott
Attorney for Applicant
Registration No. 25,220

Enclosures: As noted above

Please type a plus sign (+) inside this box +

PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if Known	
		Application Number	
		Filing Date	
		First Named Inventor	Michael P. Chrisp
		Group Art Unit	
Examiner Name			
Sheet 1	of 1	Attorney Docket Number	IL-11127

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	U.S. Patent Document Number Kind Code ² (if known)		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		5,127,728		Warren, et al.	07-07-1992	
		5,717,487		Davies	01-10-1998	
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FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ⁵ (if known)				
			WO 99/63311		Ansley, et al.	12-09-1999		

Examiner Signature		Date Considered	
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.
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